

**Search Notes****Application/Control No.**

10/752,642

**Applicant(s)/Patent under  
Reexamination**

NAKAMURA ET AL.

**Examiner**

CHRIS C. CHU

**Art Unit**

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E21.584, E21.582 & E21.174	6/4/2008	C.C.
257	758 & 751	6/4/2008	C.C.
257	762 & 763	6/4/2008	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB, USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	6/4/2008	C.C.